

# DRAM

# 16 MEG x 1 DRAM

## STATIC COLUMN

### FEATURES

- Industry standard x1 pinout, timing, functions and packages
- High-performance, CMOS silicon-gate process
- Single power supply: +5V  $\pm$ 10%
- Low power, 3mW standby; 330mW active, typical
- All inputs, outputs and clocks are fully TTL compatible
- Refresh modes:  $\overline{\text{RAS}}$ -ONLY,  $\overline{\text{CAS}}$ -BEFORE- $\overline{\text{RAS}}$  (CBR) and HIDDEN
- 4,096-cycle refresh distributed across 64ms

### OPTIONS

- Timing
  - 60ns access
  - 70ns access
  - 80ns access

### MARKING

-6  
-7  
-8

- Packages

Plastic SOJ (400 mil)

DJ

NOTE: Available in die form (commercial or military) or military ceramic packages. Please consult factory for die data sheets or refer to Micron's *Military Data Book*.

- Operating Temperature,  $T_A$   
Commercial (0°C to +70°C)

None

- Part Number Example: MT4C16M1D1DJ-6

### GENERAL DESCRIPTION

The MT4C16M1D1 is a randomly accessed solid-state memory containing 16,777,216 bits organized in a x1 configuration. During READ or WRITE cycles, each bit is uniquely addressed through the 24 address bits, which are entered 12 bits (A0-A11) at a time.  $\overline{\text{RAS}}$  is used to latch the first 12 bits and  $\overline{\text{CAS}}$  the latter 12 bits. READ and WRITE cycles are selected with the  $\overline{\text{WE}}$  input. A logic HIGH on  $\overline{\text{WE}}$  dictates READ mode while a logic LOW on  $\overline{\text{WE}}$  dictates WRITE mode. During a WRITE cycle, data in (D) is latched by the falling edge of  $\overline{\text{WE}}$  or  $\overline{\text{CAS}}$ , whichever occurs last. If  $\overline{\text{WE}}$  goes LOW prior to  $\overline{\text{CAS}}$  going LOW, the output pin remains open (High-Z) until the next  $\overline{\text{CAS}}$  cycle. If  $\overline{\text{WE}}$  goes LOW after data reaches the output pin, data out (Q) is activated and retains the selected cell data as long as  $\overline{\text{CAS}}$

### PIN ASSIGNMENT (Top View)

#### 24-Pin SOJ (Q-3)

Vcc	1	28	Vss
D	2	27	Q
NC	3	26	NC
$\overline{\text{WE}}$	4	25	$\overline{\text{CAS}}$
$\overline{\text{RAS}}$	5	24	NC
A11	6	23	A9
A10	9	20	A8
A0	10	19	A7
A1	11	18	A6
A2	12	17	A5
A3	13	16	A4
Vcc	14	15	Vss

remains LOW (regardless of  $\overline{\text{WE}}$  or  $\overline{\text{RAS}}$ ). This late  $\overline{\text{WE}}$  pulse results in a READ-WRITE cycle.

STATIC COLUMN operations allow faster data operations (READ, WRITE or READ-MODIFY-WRITE) within a row address (A0-A11) defined page boundary. After the first read, any column address transition will result in new data out. Unlike the PAGE-MODE part, which requires  $\overline{\text{CAS}}$  to be toggled for each successive PAGE-MODE access, the STATIC COLUMN part allows  $\overline{\text{CAS}}$  to be left LOW for successive STATIC COLUMN accesses. Returning  $\overline{\text{RAS}}$  HIGH terminates the STATIC COLUMN operation.

Returning  $\overline{\text{RAS}}$  and  $\overline{\text{CAS}}$  HIGH terminates a memory cycle and decreases chip current to a reduced standby level. Also, the chip is preconditioned for the next cycle during the  $\overline{\text{RAS}}$  high time. Memory cell data is retained in its correct state by maintaining power and executing any  $\overline{\text{RAS}}$  cycle (READ, WRITE,  $\overline{\text{RAS}}$ -ONLY,  $\overline{\text{CAS}}$ -BEFORE- $\overline{\text{RAS}}$  or HIDDEN refresh) so that all 4,096 combinations of  $\overline{\text{RAS}}$  addresses (A0-A11) are executed at least every 64ms, regardless of sequence. The CBR refresh cycle will invoke the internal refresh counter for automatic  $\overline{\text{RAS}}$  addressing.